

# LATS2017

18<sup>th</sup> IEEE Latin-American Test Symposium  
Bogota, Colombia, 13<sup>th</sup> - 15<sup>th</sup> March 2017



PRELIMINARY CALL FOR PAPERS



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## PRELIMINARY CALL FOR PAPERS

The IEEE Latin-American Test Symposium (LATS, previously Latin-American Test Workshop - LATW) is a recognized forum for test and fault tolerance professionals and technologists from all over the world, in particular from Latin America, to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. Presented papers are also published in the IEEE Xplore Digital Library. The best papers of the 18<sup>th</sup> LATS will be invited to re-submit to IEEE Design and Test of Computers, Journal of Electronic Testing: Theory and Applications - JETTA (Springer), Journal of Low Power Electronics - JOLPE (American Scientific Publishers), and IEEE Transactions on Computer-Aided Design (TCAD).

## Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Design and Synthesis for Testability
- Design for Electromagnetic Compatibility
- Design for Reliable Embedded Software
- Design Verification/Validation
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation/EMI
- Hardening Techniques
- Software Fault-Tolerance
- Software On-Line Testing
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization
- Hardware Security

## Paper Submission Information:

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the symposium are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions must be done via the symposium's webpage: [www.lats.ttc-events.org](http://www.lats.ttc-events.org)

Authors should send papers in the IEEE format. Detailed instructions are available at the symposium's webpage. The Program Committee also welcomes proposals for panels and special topic sessions.

For additional information, please contact one of the Program Chairs:

### Ernesto Sanchez – POLITO, Italy

[ernesto.sanchez@polito.it](mailto:ernesto.sanchez@polito.it)

### Tiago Balen - Federal University of Rio Grande do Sul, Brazil

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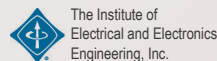
**Submission Deadline (Title and Abstract):** November 25<sup>th</sup>, 2016

**Submission HARD DEADLINE (Full paper):** December 9<sup>th</sup>, 2016

**Notification of Acceptance:** January 13<sup>th</sup>, 2017.

**Camera Ready:** January 27<sup>th</sup>, 2017.

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